

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

EXPRESS MAIL NO. EV351235065US

Appl No. : N/A Confirmation No.  
Applicant : Akio Ishikawa  
Filed : September 29, 2003  
Title : IMAGE DEFECT INSPECTION METHOD, IMAGE DEFECT  
INSPECTION APPARATUS AND APPEARANCE INSPECTION  
APPARATUS  
  
TC/A.U. : N/A  
Examiner : N/A  
  
Docket No. : 51272/DBP/A400  
Customer No. : 23363

**PRELIMINARY AMENDMENT**

Commissioner for Patents Post Office Box 7068  
P.O. Box 1450 Pasadena, CA 91109-7068  
Alexandria, VA 22313-1450 September 29, 2003

Commissioner:

Prior to examination, please amend the above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Remarks/Arguments** begin on page 3 of this paper.